

**LIST OF PRIOR ART CITED BY
APPLICANT**
(PTO-1449)

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APPLICANT(S)
Sung Bae JUN and Kyoung Ro YOON

FILING DATE
September 21, 2000

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2611

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

EXAMINER'S INITIALS	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	FILING DATE


U.S. PATENT APPLICATIONS

EXAMINER'S INITIALS	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
KB	JP 05-334374	12-17-93	Japan			X	
KB	JP 04-207878	07-29-92	Japan			X	
KB	JP 09-212349	08-15-97	Japan			X	
KB	JP 2000-217058	08-04-00	Japan			X	
KB	JP 2000-253377	09-14-00	Japan			X	
KB	JP 11-239322	08-31-99	Japan			X	
KB	JP 10-234004	09-02-98	Japan			X	
KB	JP 05-030464	02-05-93	Japan			X	
KB	JP 09-083955	03-28-97	Japan			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

EXAMINER			DATE CONSIDERED	06/08/04

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	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
KB	JP04207878	07-29-92	Japan			X	

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